Se	arcn No	ites

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/017,232	LACROIX, MICHAEL CHARLES	
Examiner	Art Unit	_
Patrick Miller	2837	

	SEAR	CHED	
Class	Subclass	Date	Examiner
			_
	•		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH))
•	DATE	EXMR
overcurrent; over/under voltage; 8-bit; DAC; vcm w/ temperature; voltage detector, etc.; state machine; all with 318/727-832	7/7/2005	PM
318 (all classes) & 388 (all classes - text search as above and according to search history printout	7/7/2005	РМ
	!	